

<b>Notice of References Cited</b>	Application/Control No. 10/840,222	Applicant(s)/Patent Under Reexamination IWAMI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,816,937	10-1998	Shimosaka et al.	473/354
*	B	US-6,093,357	07-2000	Bissonette et al.	264/248
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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